

## General Description

The AOP604 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications. A Schottky diode in parallel with the n-channel FET reduces body diode related losses.

## Features

**n-channel**      **p-channel**

$V_{DS}$  (V) = 30V    -30V

$I_D$  = 7.5A        -6.6A

$R_{DS(ON)}$

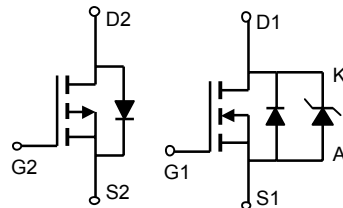
< 28m $\Omega$         < 35m $\Omega$  ( $V_{GS}$  = 10V)

< 43m $\Omega$         < 58m $\Omega$  ( $V_{GS}$  = 4.5V)

**Schottky**

$V_{DS}=30V$ ,  $I_F=3A$ ,  $V_F<0.5V@1A$

### PDIP-8



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	$T_A=25^\circ\text{C}$	7.5	A
		$T_A=70^\circ\text{C}$	6	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	-30	
Power Dissipation	$P_D$	$T_A=25^\circ\text{C}$	2.5	W
		$T_A=70^\circ\text{C}$	1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	$^\circ\text{C}$

Parameter	Symbol	Maximum Schottky	Units
Reverse Voltage	$V_{DS}$	30	V
Continuous Forward Current <sup>A</sup>	$I_D$	$T_A=25^\circ\text{C}$	A
		$T_A=70^\circ\text{C}$	
Pulsed Forward Current <sup>B</sup>	$I_{DM}$	20	
Power Dissipation <sup>A</sup>	$P_D$	$T_A=25^\circ\text{C}$	W
		$T_A=70^\circ\text{C}$	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$

Thermal Characteristics: n-channel					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	40	50	$^{\circ}C/W$
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State		67	80	$^{\circ}C/W$
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	33	40	$^{\circ}C/W$

Thermal Characteristics: p-channel					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	38	50	$^{\circ}C/W$
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State		66	80	$^{\circ}C/W$
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	30	40	$^{\circ}C/W$

Thermal Characteristics: Schottky					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	42	50	$^{\circ}C/W$
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State		70	80	$^{\circ}C/W$
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	34	40	$^{\circ}C/W$

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}C$ . The value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10s$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80  $\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}C$ . The SOA curve provides a single pulse rating.

n-channel MOSFET Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			1 5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> =250μA	1	1.8	3	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	30			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =7.5A T <sub>J</sub> =125°C		22.6	28	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6.0A		33	43	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =7.5A	12	16		S
V <sub>SD</sub>	Schottky+ Body Diode Forward Voltage	I <sub>S</sub> =1A		0.45	0.5	V
I <sub>S</sub>	Maximum Body-Diode+Schottky Continuous Current				4	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz		680		pF
C <sub>oss</sub>	Output Capacitance. (Schottky+FET)			102		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			77		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		3		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g(10V)</sub>	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =15V, I <sub>D</sub> =7.5A		13.84		nC
Q <sub>g</sub>	Total Gate Charge			6.74		nC
Q <sub>gs</sub>	Gate Source Charge			1.82		nC
Q <sub>gd</sub>	Gate Drain Charge			3.2		nC
t <sub>D(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, R <sub>L</sub> =2.0Ω, R <sub>GEN</sub> =6Ω		4.6		ns
t <sub>r</sub>	Turn-On Rise Time			4.1		ns
t <sub>D(off)</sub>	Turn-Off Delay Time			20.6		ns
t <sub>f</sub>	Turn-Off Fall Time			5.2		ns
t <sub>rr</sub>	Body Diode Reverse Recovery time	I <sub>F</sub> =7.5A, di/dt=100A/μs		16.5		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery charge	I <sub>F</sub> =7.5A, di/dt=100A/μs		7.8		nC
<b>SCHOTTKY PARAMETERS</b>						
V <sub>F</sub>	Forward Voltage Drop	I <sub>F</sub> =1.0A		0.45	0.5	V
I <sub>rm</sub>	Maximum reverse leakage current	V <sub>R</sub> =30V		0.007	0.05	mA
		V <sub>R</sub> =30V, T <sub>J</sub> =125°C		3.2	10	
		V <sub>R</sub> =30V, T <sub>J</sub> =150°C		12	20	
C <sub>T</sub>	Junction Capacitance	V <sub>R</sub> =15V		37		pF

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

p-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$ , $V_{GS}=0\text{V}$	-30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}$ , $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=-250\mu\text{A}$	-1.2	-2	-2.4	V
$I_{D(ON)}$	On state drain current	$V_{GS}=-10\text{V}$ , $V_{DS}=-5\text{V}$	30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$ , $I_D=-6.6\text{A}$ $T_J=125^\circ\text{C}$		28 37	35 45	m $\Omega$
		$V_{GS}=-4.5\text{V}$ , $I_D=-5\text{A}$		44	58	m $\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}$ , $I_D=-6.6\text{A}$		13		S
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}$ , $V_{GS}=0\text{V}$		-0.76	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-4.2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=-15\text{V}$ , $f=1\text{MHz}$		920		pF
$C_{oss}$	Output Capacitance			190		pF
$C_{rss}$	Reverse Transfer Capacitance			122		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $f=1\text{MHz}$		3.6		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{GS}=-10\text{V}$ , $V_{DS}=-15\text{V}$ , $I_D=-6.6\text{A}$		18.5		nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			9.6		nC
$Q_{gs}$	Gate Source Charge			2.7		nC
$Q_{gd}$	Gate Drain Charge			4.5		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=-10\text{V}$ , $V_{DS}=-15\text{V}$ , $R_L=2.3\Omega$ , $R_{GEN}=3\Omega$		7.7		ns
$t_r$	Turn-On Rise Time			5.7		ns
$t_{D(off)}$	Turn-Off Delay Time			20.2		ns
$t_f$	Turn-Off Fall Time			9.5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-6.6\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		20		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-6.6\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		8.8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

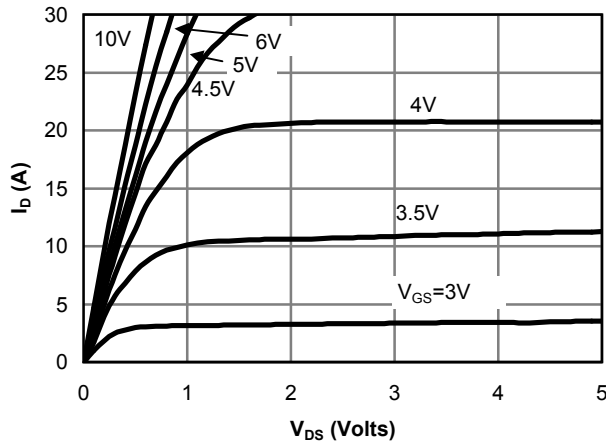
B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

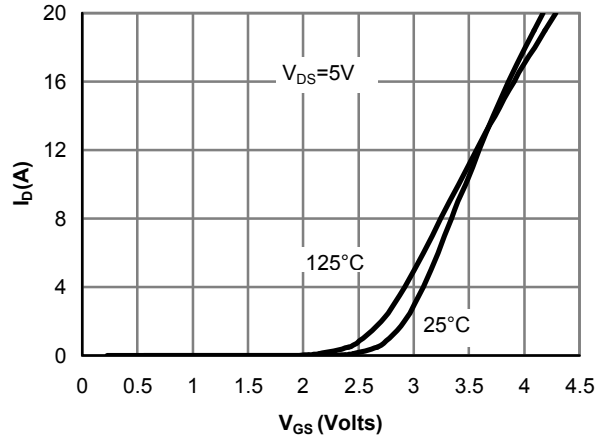
D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

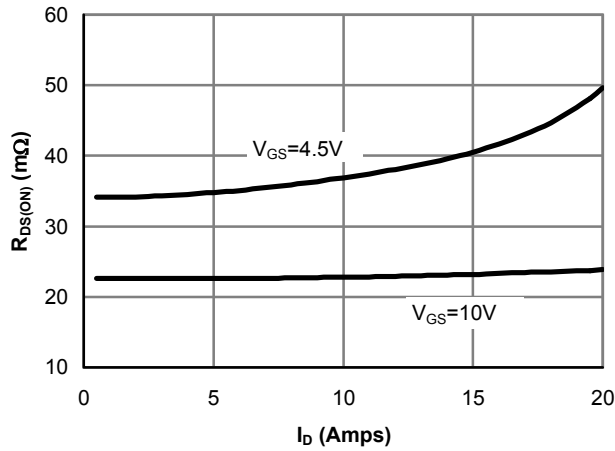
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL**



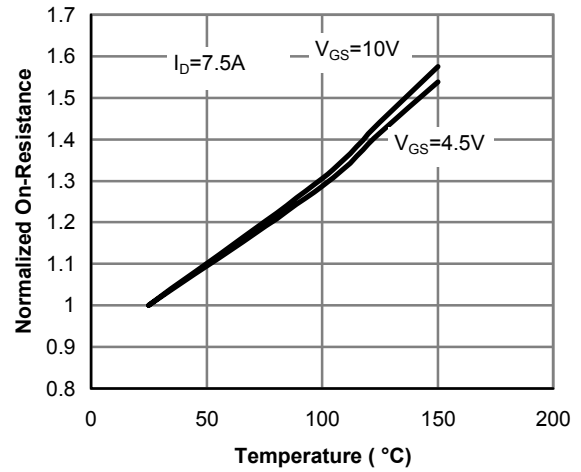
**Fig 1: On-Region Characteristics**



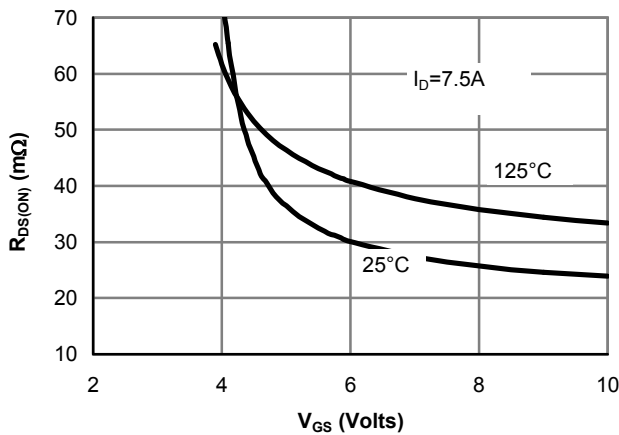
**Figure 2: Transfer Characteristics**



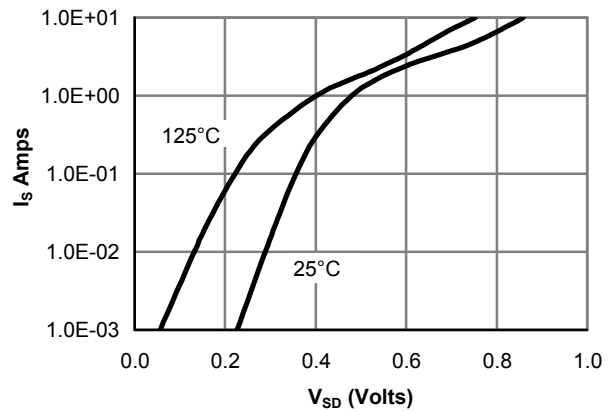
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body diode characteristics MOSFET+Schottky**

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL

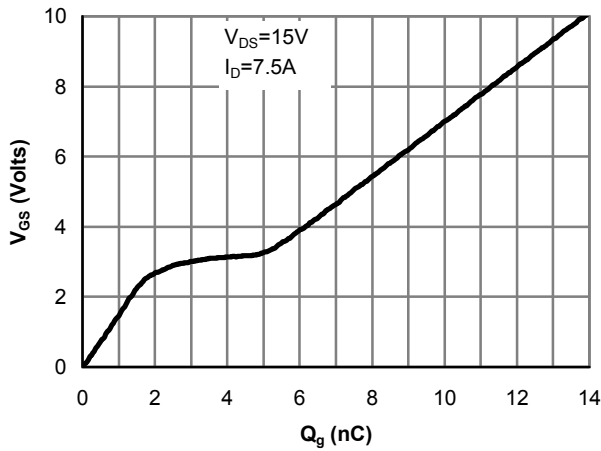


Figure 7: Gate-Charge characteristics

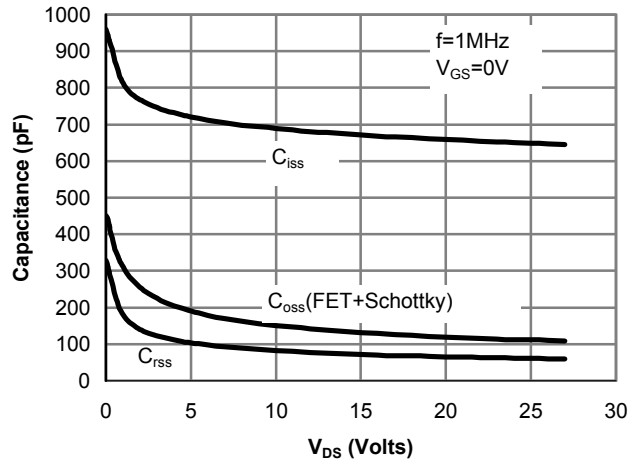


Figure 8: Capacitance Characteristics

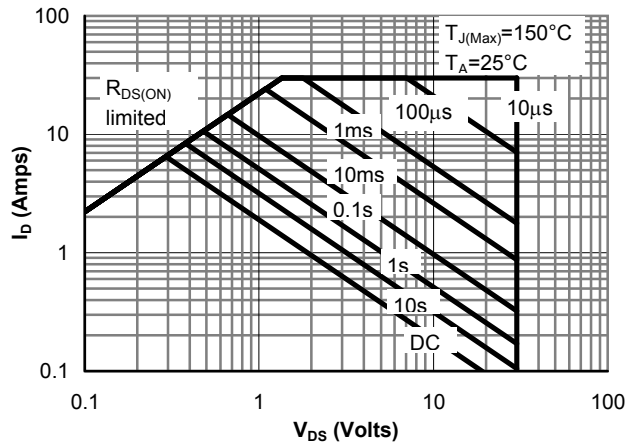


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

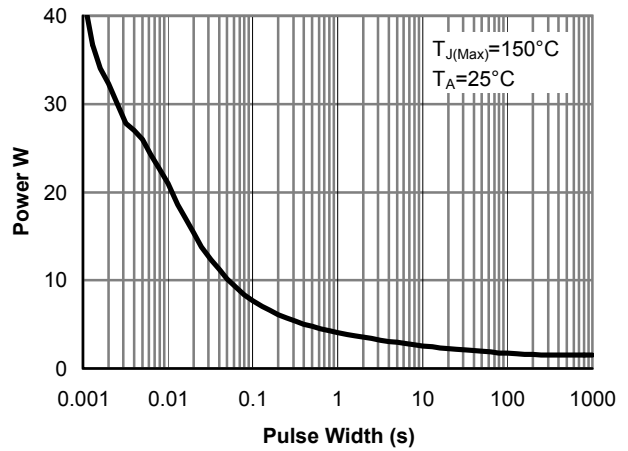


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

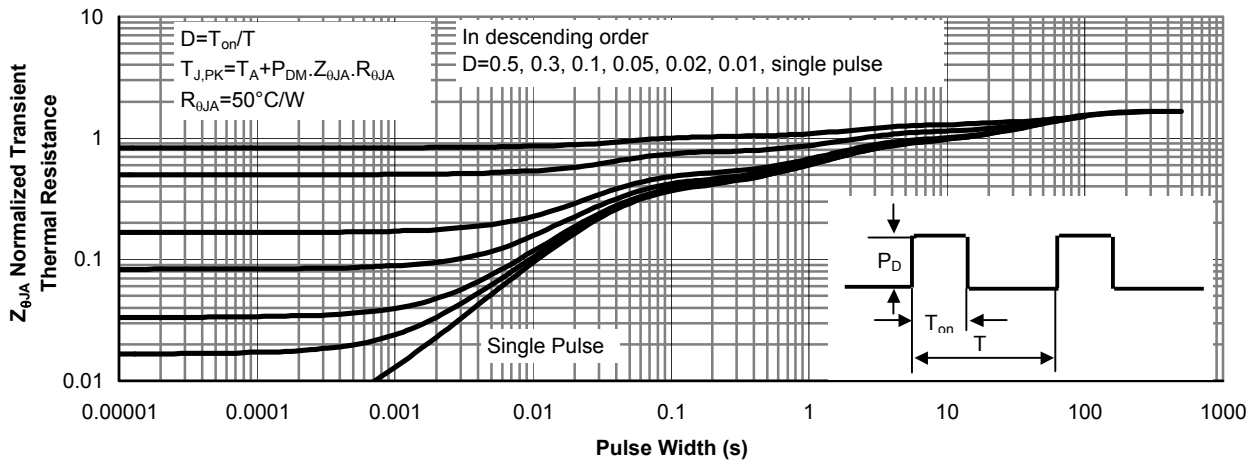


Figure 11: Normalized Maximum Transient Thermal Impedance

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

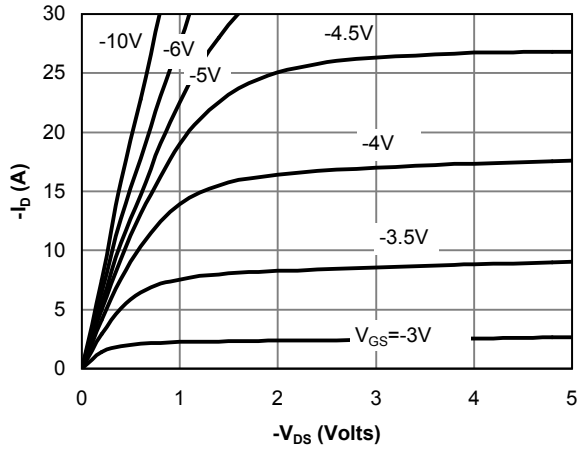


Fig 1: On-Region Characteristics

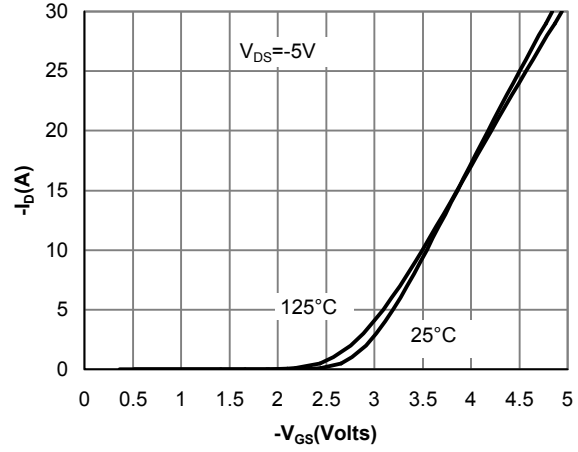


Figure 2: Transfer Characteristics

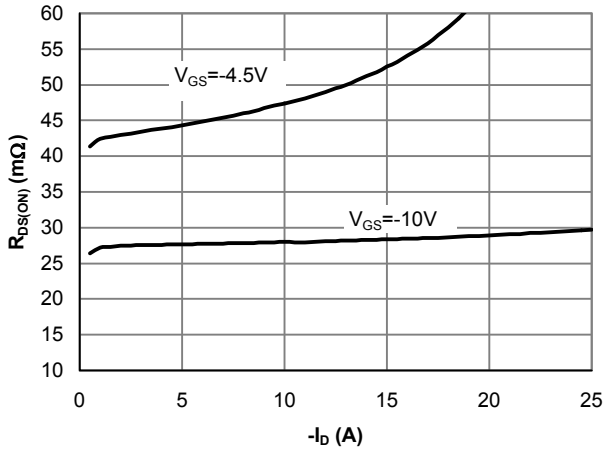


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

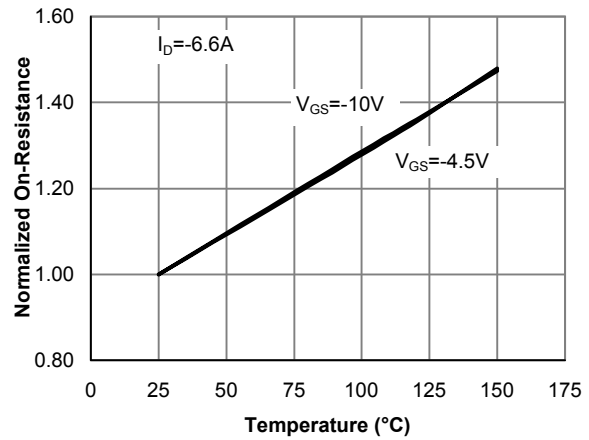


Figure 4: On-Resistance vs. Junction Temperature

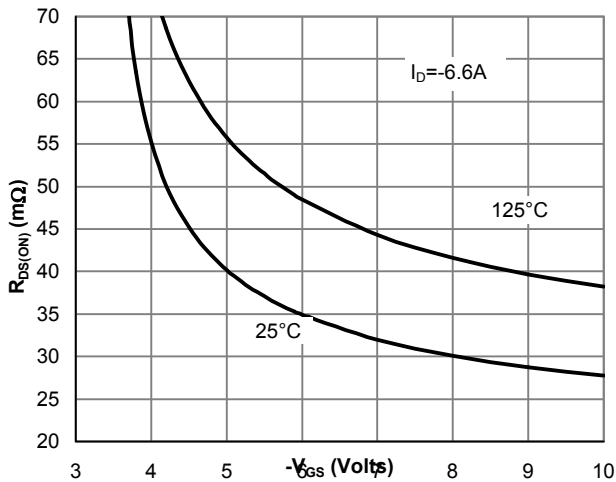


Figure 5: On-Resistance vs. Gate-Source Voltage

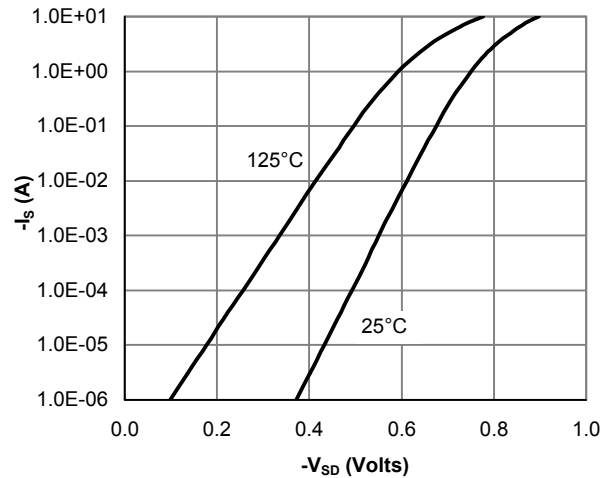


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

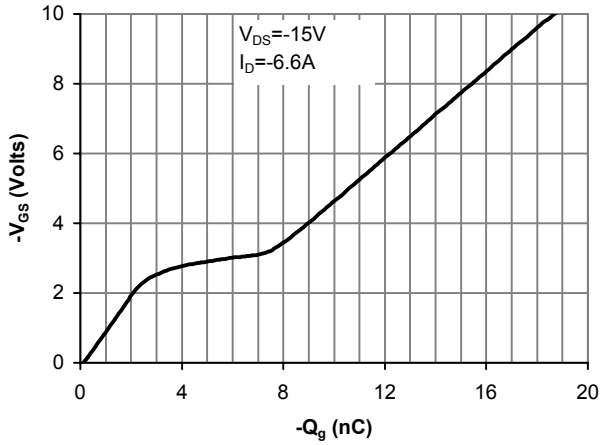


Figure 7: Gate-Charge Characteristics

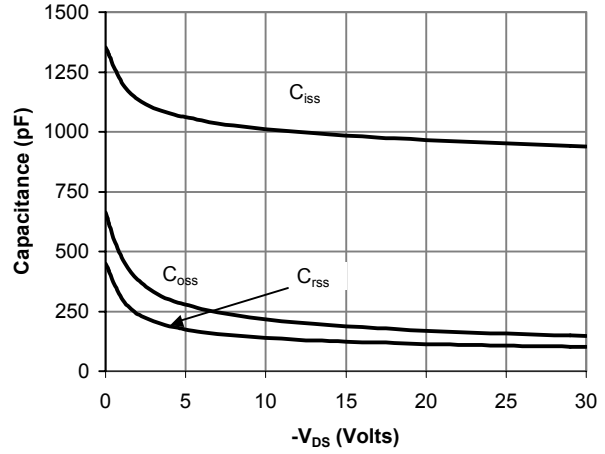


Figure 8: Capacitance Characteristics

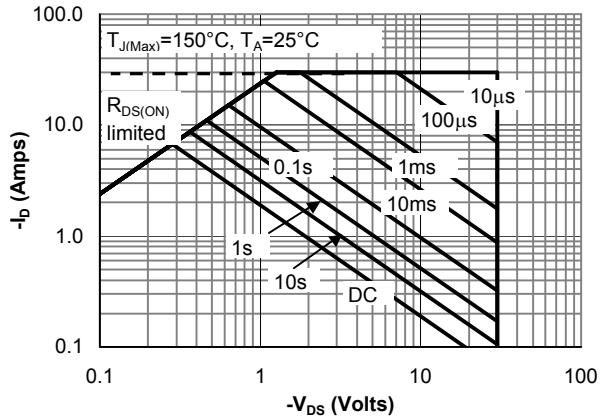


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

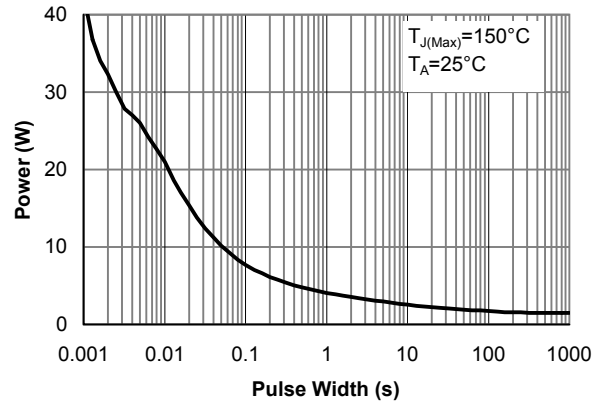


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

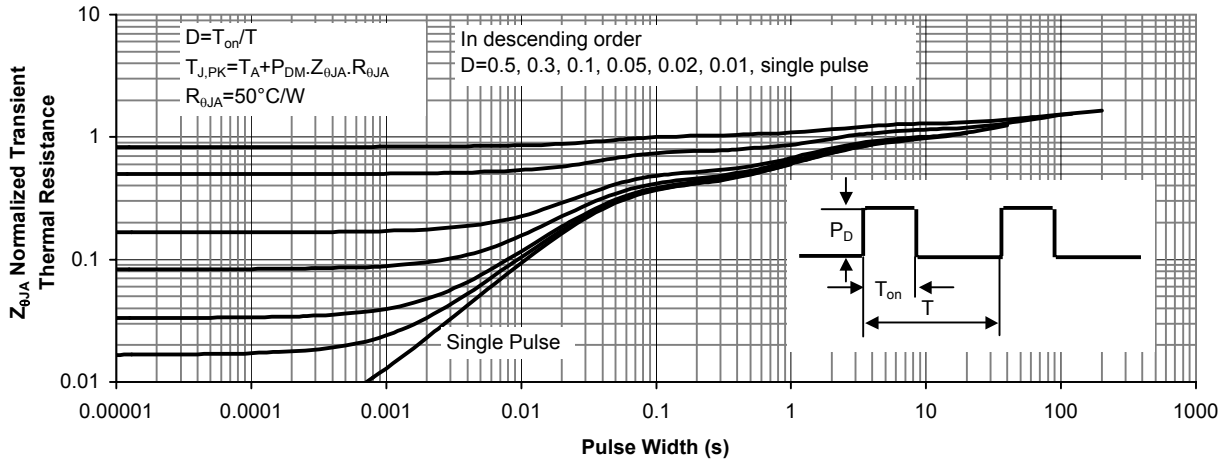


Figure 11: Normalized Maximum Transient Thermal Impedance



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: SCHOTTKY

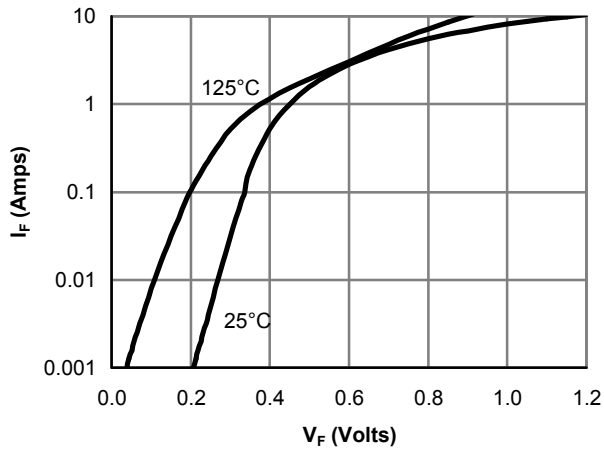


Figure 12: Schottky Forward Characteristics

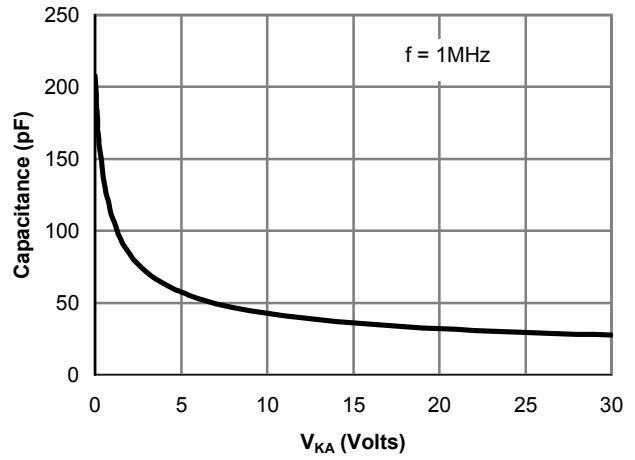


Figure 13: Schottky Capacitance Characteristics

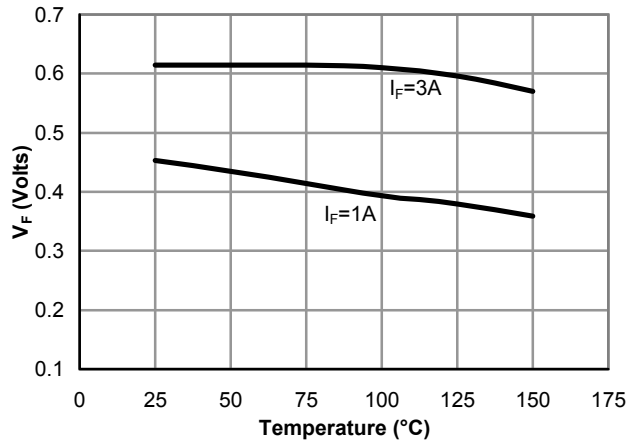


Figure 14: Schottky Forward Drop vs. Junction Temperature

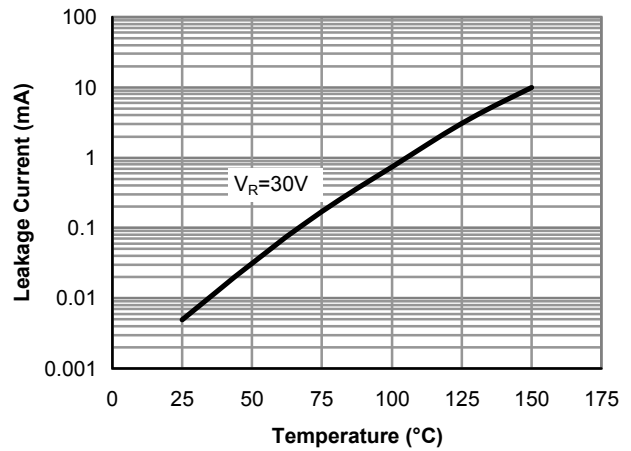


Figure 15: Schottky Leakage current vs. Junction Temperature

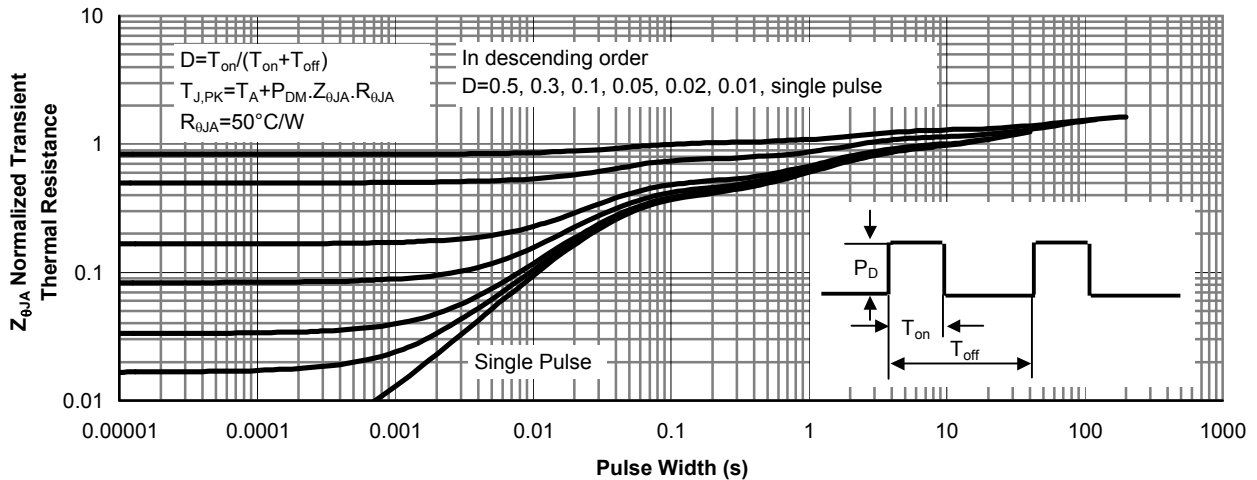
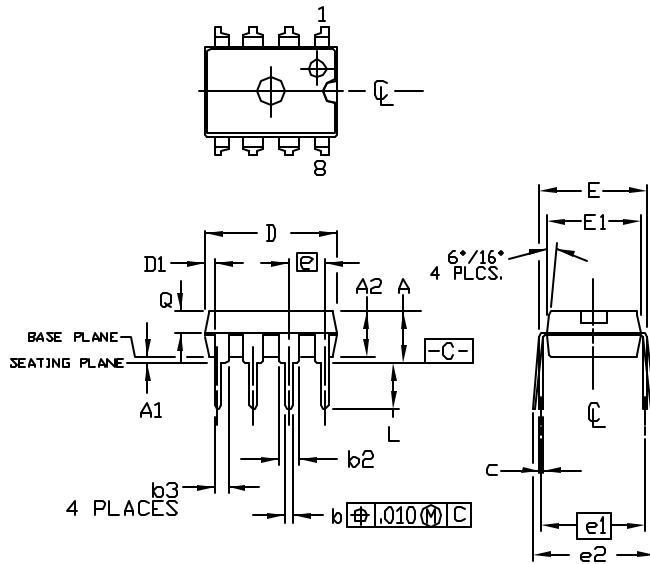


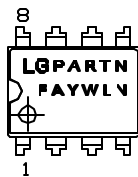
Figure 15: Schottky Normalized Maximum Transient Thermal Impedance



SYMBOL	INCHES			INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A			4.32			.170
A1	.38			.015		
A2	2.92	3.30	4.95	.115	.130	.195
b	0.41	0.46	0.51	.016	.018	.020
b1	0.36	0.46	0.51	.014	.018	.020
b2	1.40	1.52	1.65	.055	.060	.065
b3	0.76	0.99	1.14	.030	.039	.045
c	0.20	0.25	0.30	.008	.010	.012
C1	0.20	0.25	0.28	.008	.010	.011
D	9.14	9.27	9.65	.360	.365	.380
D1	0.46	0.58	0.71	.018	.023	.028
F	7.62		8.26	.300		.325
F1	6.10	6.40	6.60	.240	.252	.260
e	2.54 BSC			.100 BSC		
e1	7.62 BSC			.300 BSC		
e2			10.92			.430
L	3.18		3.43	.125		.135
N	8			8		
Q	1.40	1.52	1.65	.055	.060	.065

NOTE:  
1. LEAD FINISH: 150 MICROINCHES ( 3.8 um) MIN.  
THICKNESS OF Tin/Lead (SOLDER) PLATED ON LEAD  
2. TOLERANCE ±0.100 mm (4 mil) UNLESS OTHERWISE SPECIFIED  
3. COPLANARITY : 0.1000 mm  
4. DIMENSION L IS MEASURED IN GAGE PLANE

PACKAGE MARKING DESCRIPTION

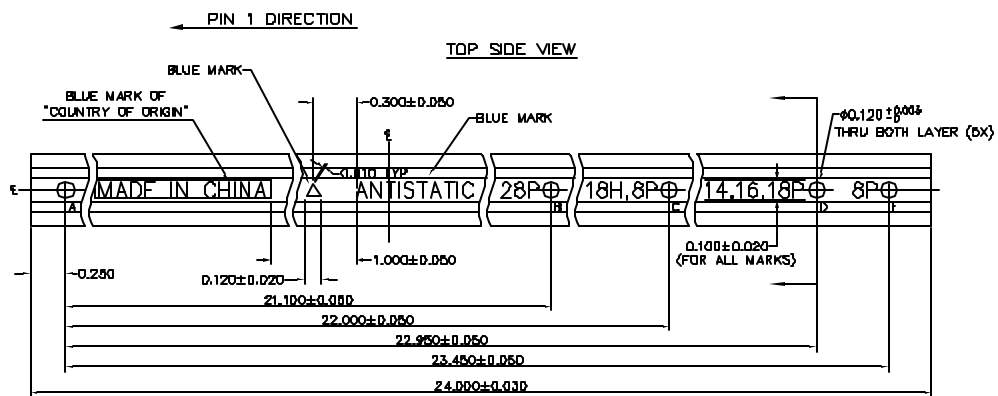


NOTE:  
LG - AOS LOGO  
PARTN - PART NUMBER CODE.  
F - FAB LOCATION  
A - ASSEMBLY LOCATION  
Y - YEAR CODE  
W - WEEK CODE.  
L N - ASSEMBLY LOT CODE

PDIP-8 PART NO. CODE

PART NO.	CODE	PART NO.	CODE	PART NO.	CODE
AOP604	P604				

PDIP-8 Tube



NOTES:

1. PLASTIC CARRIER THERMAL REQUIREMENTS TO 125F WITHOUT DISTORTION OR DETERIORATION IN ANTI-STATIC PROPERTIES.
2. CLARITY : PARTS IN TUBE TO BE CLEARLY VISIBLE IN DAYLIGHT TO THE NAKED EYE.
3. TUBE TO BE COATED (INSIDE AND OUT) WITH ANTI-STATIC AGENTS (PI-23820) AND THE SURFACE RESISTIVITY SHALL BE BETWEEN  $10^8$  TO  $10^{12}$  OHM/CM<sup>2</sup>.
4. MATL : MODIFIED ACRYLIC OR RIGID PVC.
5. FLATNESS ; TUBE TO BE FLAT WITH 1/32 INCH.
6. BLUE MARK OF "△ ANTISTATIC 28P 8P 14, 16, 18P " SHALL BE PUT ON TOP SURFACE OF TUBE AND SHALL PASS COTTON BRUSH TEST. (5 CYCLES)\*
7. TUBE WITH RIPPLE SURFACE AT PACKAGE LOADING AREA THAT AFFECT PACKAGE VISIBILITY SHALL BE REJECTABLE.
8. ALL DIMENSION ARE IN INCH.

